New Jersey Semi-Conductor Products, Inc.

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TMOS IV Power Field Effect Transistor N-Channel Enhancement-Mode Silicon Gate

This advanced "E" series of TMOS power MOSFETs is designed to withstand high energy in the avalanche and commutation modes. These new energy efficient devices also offer drain-to-source diodes with fast recovery times. Designed for low voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating area are critical, and offer additional safety margin against unexpected voltage transients.

- Internal Source-to-Drain Diode Designed to Replace External Zener Transient Suppressor — Absorbs High Energy in the Avalanche Mode — Unclamped Inductive Switching (UIS) Energy Capability Specified at 100°C.
- Commutating Safe Operating Area (CSOA) Specified for Use in Half and Full Bridge Circuits
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits





MTP25N05E

TMOS POWER FET's 25 AMPERES *DS(on) = 0.07 OHM 50 VOLTS



MAXIMUM RATINGS (TJ = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-Source Voltage	VDSS	50	Vdc
Drain-Gate Voltage (RGS = 1 MΩ)	VDGR	50	Vdc
Gate-Source Voltage — Continuous \rightarrow Non-repetitive (tp \leq 50 µs)	VGS VGSM	± 20 ± 40	Vdc Vpk
Drain Current — Continuous — Puised	a Mol	25 80	Adc
Total Power Dissipation (« Tc = 25°C Derate above 25°C	PD	100 0.8	Watts W/°C
Operating and Storage Temperature Range	TJ, Tstg	-65 to 150	°C
HERMAL CHARACTERISTICS			•
Thermal Resistance — Junction to Case — Junction to Ambient	R _Ø JC R _Ø JA	1.25 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	Т	275	•C

Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. SOA Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design.



NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.

Quality Semi-Conductors

MTP25N05E

ELECTRICAL CHARACTERIS	TICS (T _C = 25°C unless otherwise noted	d) (t

Characteristic		Symbol	Min	Max	Unit
OFF CHARACTERISTICS					
Drain-Source Breakdown Voltage (VGS = 0, ID = 0.25 mA)		V(BR)DSS	50 	. –	Vdc
Zero Gato Voltage Drain Current (VDS = Rated VDSS, VGS = 0) (VDS = Rated VDSS, VGS = 0, TJ = 125°C)		DSS	=	10 [°] 100	μA
Gate-Body Leakage Current, Forward (VGSF = 20 Vdc, VDS = 0)		IGSSF	-	100	nAdo
Gate-Body Leakage Current, Reverse (VGSR = 20 Vdc, VDS = 0)		IGSSR	-	100	nAda
ON CHARACTERISTICS*			•	· · · ·	
Gate Threshold Voltage (VDS = VGS, ID = 250 µA, TJ = 100	0°C)	VGS(th)	2 1.5	4 3.5	Vdc
Static Drsin-Source On-Resistance (VGS = 10 Vdc, ID = 16 Adc)		(DS(on)		0.07	Ohm
Drain-Source On-Voltage (V _{GS} = 10 V) (I _D = 25 Adc) (I _D = 12.5 Adc, T _J = 100°C)		VDS(on)	_	2 1	Vdc
Forward Transconductance (VDS = 1.7	75 V. In = 16 A)	0 _{FS}	9		mho
DRAIN-TO-SOURCE AVALANCHE CHARA		.1	·	•	
Unclamped Drain-to-Source Avalanche Energy See Figures 14 and 15 (ID = 80 A, VDD = 25 V, TC = 25°C, Single Pulse, Non-repetitive) (ID = 25 A, VDD = 25 V, TC = 25°C, P.W. $\leq 200 \ \mu$ s, Duty Cycle $\leq 1\%$) (ID = 10 A, VDD = 25 V, TC = 100°C, P.W. $\leq 200 \ \mu$ s, Duty Cycle $\leq 1\%$)		WDSR		90 200 90	mJ
DYNAMIC CHARACTERISTICS		<u> </u>	· <u></u>		
Input Capacitance	(V _{DS} = 25 V, V _{GS} = 0,	Ciss		1600	ρF
Output Capacitance	f = 1 MHz)	Coss	—	800	
Reverse Transfer Capacitance	See Figure 16	Crss		200	
SWITCHING CHARACTERISTICS* (TJ =	100°C)				
Turn-On Delay Time		td(on)	-	25	ns
Risé Time	(V _{DD} = 25 V, I <u>D</u> = 16 A R _{gen} ⇒ 15 ohms)	tr		35	
Turn-Off Delay Time	See Figure 9	td(off)		45	
Fail Time		tf	-	35	
Total Gate Charge	{V _{DS} = 0.8 Rated V _{DSS} , I _D − Rated I _D , V _{GS} − 10 V) See Figures 17 and 18	0.9	26 (Тур)	30	nC
Gate-Source Charge		Q _{gs}	14 (Typ)		
Gate-Drain Charge		o _{gd}	12 (Typ)		
SOURCE DRAIN DIODE CHARACTERIST	105-				
Forward On-Voltage	(I _S = 25 A	VSD	1.3 (Typ)	1.5	Vde
Forward Turn-On Time	(IS = 26 A VGS ⊨ 0)	ton	Limited	by stray in	luctance
Reverse Recovery Time		ter	160 (Typ)	—	ns
INTERNAL PACKAGE INDUCTANCE					_
Internal Drein Inductance (Measured from the contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die)		La	3.5 (Түр) 4.5 (Түр)	=	nH
Internal Source Inductance (Measured from the source lead 0.25" from package to source bond pad.		La	7.5 (Typ)		

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*Pulse Test: Pulse Width < 300 µs, Duty Cycle < 2%.